

<b>Notice of References Cited</b>	Application/Control No. 10/765,919	Applicant(s)/Patent Under Reexamination HATAKEYAMA ET AL.	
	Examiner Sin J. Lee	Art Unit 1752	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0068124 A1	04-2004	Hasegawa et al.	549/397
*	C	US-2002/0132182 A1	09-2002	Nishi et al.	430/270.1
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
/	U	DERWENT English abstract for JP 2001-278918 (Hatakeyama et al).
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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